Raman spectroscopy of epitaxial Zn_xMg_{x-1}O layers doped with V-group elements grown by MBE

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Zinc oxide has attracted more and more attention due to its interesting properties: it is a direct wide band-gap (3.37 eV) semiconductor with chemical and thermal stability in harsh environments. Possible applications of this material include short wavelength optoelectronic devices, mostly blue and white light emitting diodes [1], ultraviolet detectors [2] and more. However, technology meets large problems with fabrication of p-type ZnO, which is crucial for developing p-n junctions. The number of reports about stable p-type ZnO based materials is limited, yet some progress has been achieved. Among the proposed acceptor doping materials are, inter alia, Arsenic, Nitrogen and Antimony.

In our work, micro-Raman spectroscopy was applied to study structural properties of epitaxial $Zn_XMg_{X-1}O$ layers doped with V-group elements. The layers were grown on commercial GaN/Al₂O₃ substrates by plasma assisted Molecular Beam Epitaxy (PA - MBE). The substrates were chemically cleaned before growth and then out-gassed at 700°C in high vacuum. Knudsen cells were used as sources of arsenic, magnesium and zinc and an *rf* plasma cells as sources of oxygen and nitrogen. The power of the O₂ and N₂ *rf* sources were 350 W and 400 W, respectively. The growth temperature was about 450°C. Magnesium concentration was examined by low temperature luminescence as well as Rutherford backscattering spectrometry measurements. A reference GaN/Al2O3 sample was also studied for comparison.

Room temperature Raman spectra were measured from 300 cm^{-1} to 1200 cm^{-1} in the backscattering geometry, with an excitation of the 514 nm Ar+ laser line without polarization detection. Phonon modes A1(LO) and E1(LO) were observed and it was found that both were red shifted with respect to the phonon modes of bulk ZnO. Possible origin of the shift was discussed.

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